Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination
10/527,062	FURUISHI ET AL.
Examiner	Art Unit
Nyaamah Grazier	1626

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Class	Subclass	Date	Examiner
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514	423	2/28/2007	NG
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INTERFERENCE SEARCHED					
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548	533	834/1	RN-		
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SEARCH (INCLUDING SEAR		<b>Y)</b>		
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Inventor Name Search	2/28/2007	NG		
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